

IPB120P04P4L-03 IPI120P04P4L-03, IPP120P04P4L-03

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	1.1	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	-	62	
SMD version, device on PCB	R_{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ³⁾	-	-	40	Ī

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS} =0V, I_D = -1mA	-40	ı	ı	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = -340 \mu {\rm A}$	-1.2	-1.7	-2.2	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =-32V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C	1	-0.05	-1	μΑ
		V_{DS} =-32V, V_{GS} =0V, T_{j} =125°C ²⁾	ı	-20	-200	
Gate-source leakage current	I _{GSS}	V_{GS} =-16V, V_{DS} =0V	1	1	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =-4.5V, I _D =-100A	-	4.0	5.2	mΩ
		$V_{\rm GS}$ =-4.5V, $I_{\rm D}$ =-100A, SMD version	ı	3.7	4.9	
		V _{GS} =-10V, I _D =-100A	1	2.9	3.4	
		$V_{\rm GS}$ =-10V, $I_{\rm D}$ =-100A, SMD version	-	2.6	3.1	

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Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss	$V_{\rm GS}$ =0V, $V_{\rm DS}$ =-25V, f =1MHz	-	11380	15000	pF
Output capacitance	Coss		-	3410	5000	
Reverse transfer capacitance	C _{rss}		-	135	270	
Turn-on delay time	$t_{\rm d(on)}$	$V_{\rm DD}$ =-20V, $V_{\rm GS}$ =-10V, $I_{\rm D}$ =-120A, $R_{\rm G}$ =3.5 Ω	-	21	-	ns
Rise time	t _r		-	16	-	
Turn-off delay time	$t_{d(off)}$		-	85	-	
Fall time	t_{f}		-	57	-	
Gate Charge Characteristics ²⁾	To	<u> </u>		10		L
Gate to source charge	Q _{gs}	$V_{\rm DD}$ =-32V, $I_{\rm D}$ =-120A, $V_{\rm GS}$ =0 to -10V	-	40	52	nC
Gate to drain charge	Q _{gd}		-	32	64	
Gate charge total	Qg		-	180	234	
Gate plateau voltage	$V_{ m plateau}$		-	3.5	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	- T _C =25°C	-	-	-120	Α
Diode pulse current ²⁾	I _{S,pulse}		1	-	-480	
Diode forward voltage	V _{SD}	$V_{\rm GS}$ =0V, $I_{\rm F}$ =-100A, $T_{\rm j}$ =25°C	-	-1	-1.3	V
Reverse recovery time ²⁾	t _{rr}	V_{R} =-20V, I_{F} =-50A, di_{F}/dt =-100A/ μ s	-	54		ns

 $^{^{1)}}$ Current is limited by bondwire; with an $R_{\rm thJC}$ = 1.1K/W the chip is able to carry -171A at 25°C.

²⁾ Defined by design. Not subject to production test.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



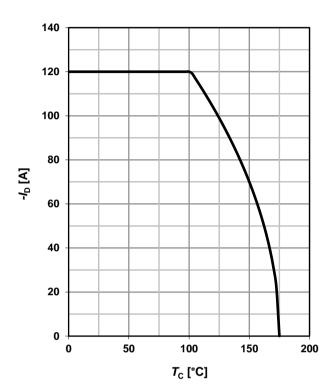
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \le -6V$$

160 140 120 100 P_{tot} [W] 80 60 40 20 0 0 50 100 150 200 *T*_C [°C]

2 Drain current

$$I_D = f(T_C); V_{GS} \le -6V; SMD$$



3 Safe operating area

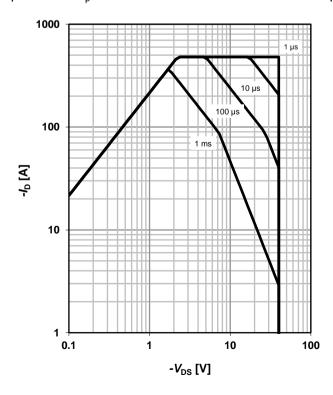
$$I_D = f(V_{DS}); T_C = 25 \,^{\circ}C; D = 0; SMD$$

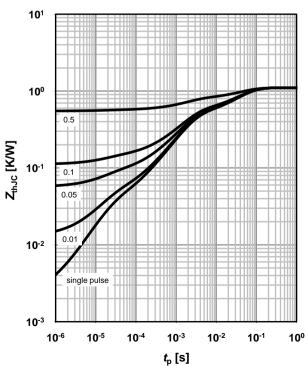
parameter: t_p

4 Max. transient thermal impedance

$$Z_{thJC} = f(t_p)$$

parameter: $D=t_p/T$







5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 \text{ °C}; SMD$

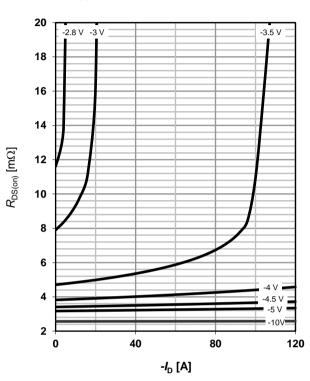
parameter: V_{GS}

640 560 480 400 <u>~</u> 320 -4 V 240 160 -3.5 V 80 -3 V 0 2 3 5 *-V*_{DS} [V]

6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ °C}; SMD$

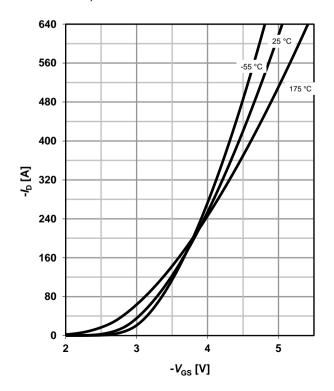
parameter: V_{GS}



7 Typ. transfer characteristics

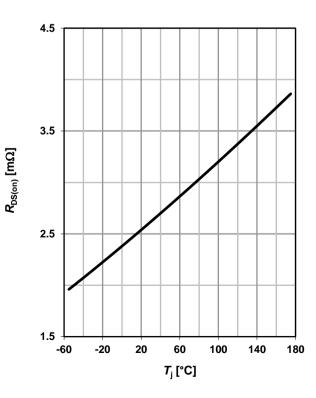
 $I_{D} = f(V_{GS}); V_{DS} = -6V$

parameter: T_i



8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_j); I_D = -100 \text{ A}; V_{GS} = -10 \text{ V}; SMD$





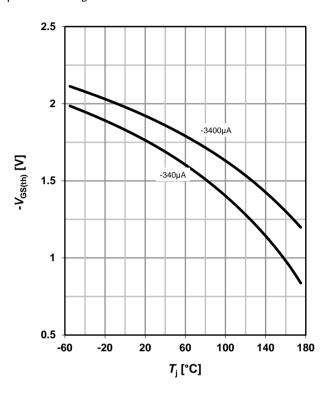
9 Typ. gate threshold voltage

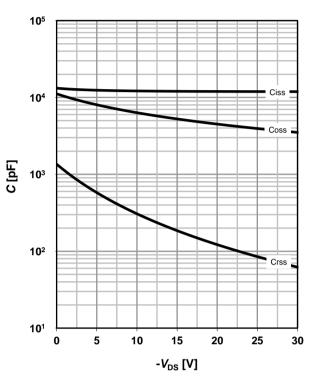
 $V_{GS(th)} = f(T_i); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

$$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$$





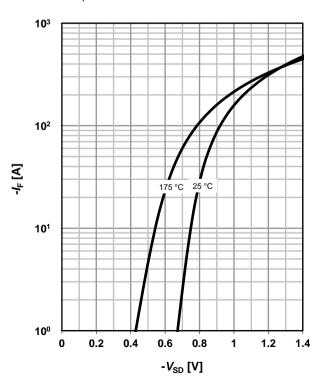
11 Typical forward diode characteristicis

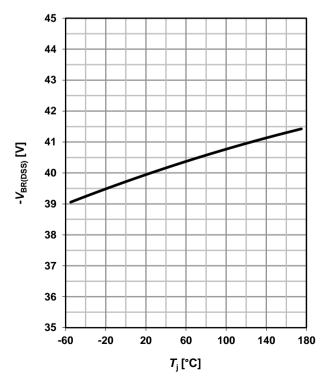
 $IF = f(V_{SD})$

parameter: T_i

12 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = -1 \text{ mA}$$





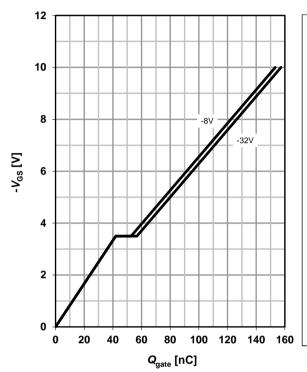


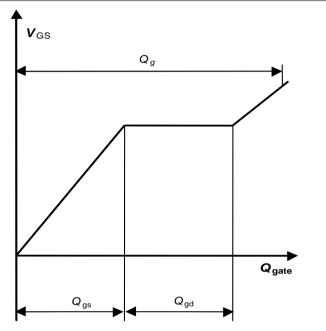
13 Typ. gate charge

14 Gate charge waveforms

 $V_{GS} = f(Q_{gate}); I_D = -120 \text{ A pulsed}$

parameter: V_{DD}







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Revision History

Version		Date	Changes		
	1.0	24.01.2011	Final Data Sheet		
	1.1	27.05.2015	Update of marking		
	1.2	03.07.2019	V _{GS} changed		